

Application/Control No.	Applicant(s)/Patent under Reexamination
10/560,051	OKABE ET AL.
Examiner	Art Unit
Son T. Nauven	36/3

SEARCHED					
Class	Subclass	Date	Examiner		
47	60 61	3/25/2009	STN		
	17 19.2				
	19.1				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	7	71			

SEARCH NO (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
IPC foreign search and text search, see printouts	3/25/2009	STN